

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Application No.	10/582,588
Filing Date	June 09, 2006
First Named Inventor	James S. Williams et al.
Art Unit	Unknown
Examiner	Unknown
Attorney Docket No.	DAVI258.003APC

(Multiple sheets used when necessary)

SHEET 1 OF 2

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
	1	5,216,631	12-01-1993	John W. Silwa Jr.	
	2	5,307,311	04-26-1994	Sliwa, Jr.	
	3	5,583,477	11-10-1998	Binnig et al.	
	4	6,665,258	12-16-2003	Dietzel et al.	
	5	D450,087	11-06-2001	Trenti Luigi	
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	7	2003/0214857 A1	11-20-2003	Horie et al.	
	8	2003/0219937 A1	11-27-2003	Peterson et al.	
	9	2004/136277	07-15-2004	Gerd K Binnig et al.	

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T <sup>1</sup>
	10	CN 1442853	09-17-2003	Horie Michikazu		
	11	EP 1343154	10-25-2006	Horie Michikazu et al.		
	12	EP 1371062	02-22-2006	Gerd K. Binnig et al.		
	13	DE 100 29 593 A1	01-18-2001	Andreas Dietzel et al.		
	14	JP 4289580 (abstract and figure only)	10-14-1992	John W. Sliwa Jr.		
	15	JP 2004/203011 (abstract only)	07-22-2004	Horie Michikazu et al.		
	16	WO 2002/077988	10-03-2002	Gerd K. Binnig et al.		
	17	WO 2003/098664	11-27-2003	Jeffrey Peterson et al.		

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>1</sup>
	18	P.Vettiger et al, <i>The "Millipede"-Nanotechnology Entering Data Storage</i> IEEE Transactions on Nanotechnology, 1(1), pp.39-55, 2002	
	19	M.Durandurdu et al, <i>High-Pressure phases of Amorphous and Crystalline Silicon</i> Physical Review B, 67(21), June 2003	

Examiner Signature

Date Considered

\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

T<sup>1</sup> - Place a check mark in this area when an English language Translation is attached.

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	20	T. Juliano et al, <i>Effect of Indentation Unloading Conditions on Phase Transformation Induced Events in Silicon</i> Journal of Material Research, 18(5), pp.1-36,2002	
	21	V. Domnich et al, <i>Pressure-Induced Structural Phase Transition of Paracrystalline Silicon</i> Physical Review B, 66(20), November 2002	
	22	J.S. Williams et al, <i>Mechanical Property Characterization of Crystalline, Ion Implantation Amorphised and Annealed Relaxed Silicon with Spherical Indenters</i> Pro. Material Research Society Symposium. 308, pp.571-6,1993	
	23	H. Kado et al, <i>Nanometer-Scale Recording on Chalcogenide Films with an atomic Force Microscope</i> (abstract) Applied Physics Letters, 66(22), pp.2961-2, May 1995	
	24	International Search Report for PCT/AU2004/001735, filed on February 15, 2005 in 5 pages.	

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